- Permits Multiplexing From N Lines to One Line
- Performs Parallel-to-Serial Conversion
- Flow-Through Architecture Optimizes
 PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

Each of these data selectors/multiplexers contains inverters and drivers to supply full binary decoding data selection to the AND-OR gates. Separate output control inputs are provided for each of the two four-line sections.

The three-state outputs can interface with and drive data lines of bus-organized systems. With all but one of the common outputs disabled (at a high-impedance state), the low-impedance of the single enabled output will drive the bus line to a high or low logic level. Each output has its own strobe (\overline{G}) . The output is disabled when its strobe is high.

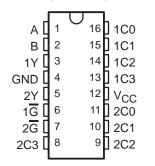
The 54AC11253 is characterized for operation over the full military temperature range of -55° C to 125°C. The 74AC11253 is characterized for operation from -40° C to 85°C.

FUNCTION TABLE

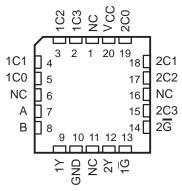
SELECT INPUTS		DATA INPUTS				OUTPUT CONTROL	OUTPUT
В	Α	C0	C1	C2	C3	G	'
Х	Х	Х	Х	Х	Х	Н	Z
L	L	L	Χ	Χ	Χ	L	L
L	L	Н	Χ	Χ	Χ	L	Н
L	Н	Х	L	Χ	Χ	L	L
L	Н	Х	Н	Χ	Χ	L	Н
Н	L	Х	Χ	L	Χ	L	L
Н	L	Х	Χ	Н	Χ	L	Н
Н	Н	Х	X	Χ	L	L	L
Н	Н	Х	Χ	Χ	Н	L	Н

Address inputs A and B are common to both sections.

54AC11253 . . . J PACKAGE 74AC11253 . . . D OR N PACKAGE (TOP VIEW)

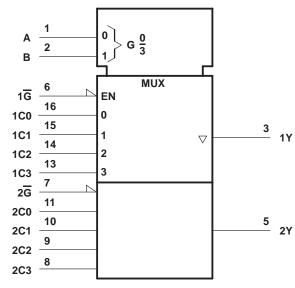


54AC11253 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic symbol†



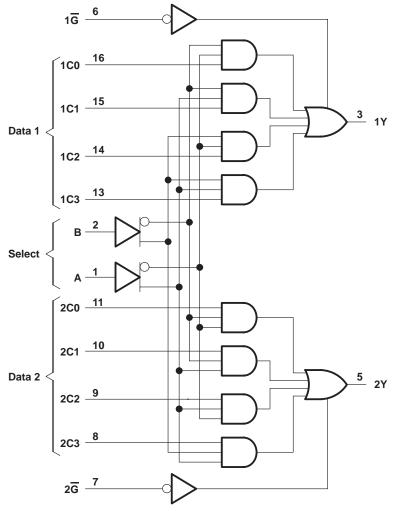
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

EPIC is a trademark of Texas Instruments Incorporated.



logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC})	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 50 mA
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTE 1: The input and output voltage ratings may be exceeded provided the input and output current ratings are observed.

recommended operating conditions

			54	AC1125	3	74AC11253			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		3	5	5.5	3	5	5.5	V	
		V _{CC} = 3 V	2.1			2.1				
ViH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V	
		V _{CC} = 5.5 V	3.85			3.85				
		V _{CC} = 3 V			0.9			0.9		
VIL	Low-level input voltage	V _{CC} = 4.5 V			1.35			1.35	V	
		V _{CC} = 5.5 V			1.65			1.65		
٧ _I	Input voltage		0		VCC	0		VCC	V	
٧o	Output voltage		0		Vcc	0		VCC	V	
		V _{CC} = 3 V			-4			-4		
IOH	High-level output current	V _{CC} = 4.5 V			-24			-24	mA	
		V _{CC} = 5.5 V			-24			-24		
		V _{CC} = 3 V			12			12		
loL	Low-level output current	V _{CC} = 4.5 V			24			24	mA	
		V _{CC} = 5.5 V			24			24		
Δt/Δν	Input transition rise or fall rate	·	0		10	0		10	ns/V	
TA	Operating free-air temperature		-55		125	-40		85	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST COMPLIANCE	V	T _A = 25°C			54AC11253		74AC11253		UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		3 V	2.9			2.9		2.9		
	I _{OH} = - 50 μA	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
V	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		V
VOH	1011 - 24 mA	4.5 V	3.94			3.7		3.8		V
	I _{OH} = - 24 mA		4.94			4.7		4.8		
	I _{OH} = - 50 mA [†]	5.5 V				3.85				
	I _{OH} = - 75 mA [†]	5.5 V						3.85		
		3 V			0.1		0.1		0.1	V
	$I_{OL} = 50 \mu A$	4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
Va	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	
VOL	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	V
	10L = 24 111A	5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65	
loz	$V_O = V_{CC}$ or GND	5.5 V			± 0.5		± 10		± 5	μΑ
lį	$V_I = V_{CC}$ or GND	5.5 V			± 0.1		± 1		± 1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		160		80	μΑ
Ci	$V_I = V_{CC}$ or GND	5 V		3.5						рF
Co	V _O = V _{CC} or GND	5 V		8						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



54AC11253, 74AC11253 DUAL 1-OF-4 DATA SELECTORS/MULTIPLEXERS WITH 3-STATE OUTPUTS

SCAS041A - MAY 1988 - REVISED APRIL 1993

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			54AC11253		74AC11253		UNIT
(INPUT)		(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or B	Y	1.5	7.1	9.7	1.5	11.7	1.5	11	ns
^t PHL			1.5	7.5	10.1	1.5	12.1	1.5	11.4	
^t PLH	Data (Any C)	Y	1.5	6.8	8.3	1.5	9.9	1.5	9.3	
^t PHL			1.5	7	8.8	1.5	10.3	1.5	9.6	ns
^t PZH	ĪG	~	1.5	4.8	6.2	1.5	7.2	1.5	6.8	ns
t _{PZL}	G	Y	1.5	5.8	7.4	1.5	8.7	1.5	8.2	115
^t PHZ	G	V	1.5	5	6.3	1.5	7	1.5	6.7	ns
^t PLZ	G	ı	1.5	5.2	6.5	1.5	7.2	1.5	6.9	115

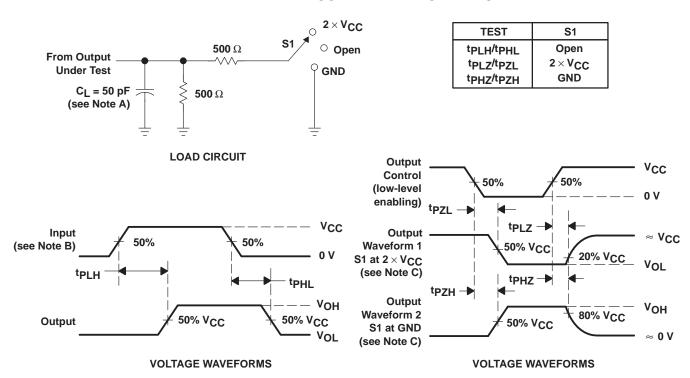
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			54AC11253		74AC11253		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	A or B	Υ	1.5	4.9	7	1.5	8.3	1.5	7.9	ne
^t PHL			1.5	5.2	7.3	1.5	8.7	1.5	8.2	ns
^t PLH	Data (Any C)	Y	1.5	4.5	5.9	1.5	7.1	1.5	6.6	ns
^t PHL			1.5	4.8	6.3	1.5	7.3	1.5	6.9	115
^t PZH	G	Y	1.5	3.4	4.6	1.5	6.4	1.5	5.1	ns
^t PZL	G		1.5	4	5.3	1.5	6.1	1.5	5.8	115
^t PHZ	G	Υ	1.5	4.7	6	1.5	6.6	1.5	6.3	no
^t PLZ]		1.5	4.6	5.9	1.5	6.4	1.5	6.2	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT	
<u> </u>	Dower dissipation conscitance per multipleyer	Outputs enabled	C _I = 50 pF. f = 1 MHz	31	~F
Cpd Power dissipation capacitance pe	Power dissipation capacitance per multiplexer	Outputs disabled	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	11	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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